

Sulfuric Acid 96%  
CMOS



Material No.: 9684-03  
Batch No.: 0000041312  
Manufactured Date: 2013/03/14  
Retest Date: 2018/03/13

## Certificate of Analysis

Test	Specification	Result
Assay (H <sub>2</sub> SO <sub>4</sub> )	95.0 – 97.0 %	96.4
Color (APHA)	<= 10	6
Residue after Ignition	<= 2 ppm	<1
Chloride (Cl)	<= 0.1 ppm	<0.1
Nitrate (NO <sub>3</sub> )	<= 0.2 ppm	<0.1
Phosphate (PO <sub>4</sub> )	<= 0.3 ppm	<0.1
Trace Impurities – Aluminum (Al)	<= 50.0 ppb	< 5.0
Arsenic and Antimony (as As)	<= 5 ppb	< 2
Trace Impurities – Barium (Ba)	<= 10.0 ppb	< 1.0
Trace Impurities – Beryllium (Be)	<= 10.0 ppb	< 1.0
Trace Impurities – Bismuth (Bi)	<= 20.0 ppb	< 10.0
Trace Impurities – Boron (B)	<= 10.0 ppb	< 5.0
Trace Impurities – Cadmium (Cd)	<= 10.0 ppb	< 1.0
Trace Impurities – Calcium (Ca)	<= 50.0 ppb	9.3
Trace Impurities – Chromium (Cr)	<= 50.0 ppb	< 1.0
Trace Impurities – Cobalt (Co)	<= 10.0 ppb	< 1.0
Trace Impurities – Copper (Cu)	<= 10.0 ppb	< 1.0
Trace Impurities – Gallium (Ga)	<= 10.0 ppb	< 1.0
Trace Impurities – Germanium (Ge)	<= 10.0 ppb	< 10.0
Trace Impurities – Gold (Au)	<= 20.0 ppb	< 5.0
Heavy Metals (as Pb)	<= 200 ppb	< 50
Trace Impurities – Iron (Fe)	<= 100.0 ppb	2.1
Trace Impurities – Lead (Pb)	<= 20.0 ppb	< 10.0
Trace Impurities – Lithium (Li)	<= 10.0 ppb	< 1.0

Test	Specification	Result
Trace Impurities – Magnesium (Mg)	<= 50.0 ppb	< 1.0
Trace Impurities – Manganese (Mn)	<= 10.0 ppb	< 1.0
Trace Impurities – Mercury (Hg)	<= 5.0 ppb	<0.1
Trace Impurities – Molybdenum (Mo)	<= 10.0 ppb	< 5.0
Trace Impurities – Nickel (Ni)	<= 10.0 ppb	< 5.0
Trace Impurities – Niobium (Nb)	<= 10.0 ppb	< 1.0
Trace Impurities – Potassium (K)	<= 50.0 ppb	< 10.0
Trace Impurities – Silicon (Si)	<= 50.0 ppb	< 10.0
Trace Impurities – Silver (Ag)	<= 10.0 ppb	< 1.0
Trace Impurities – Sodium (Na)	<= 100.0 ppb	31.9
Trace Impurities – Strontium (Sr)	<= 10.0 ppb	< 1.0
Trace Impurities – Tantalum (Ta)	<= 10.0 ppb	< 5.0
Trace Impurities – Thallium (Tl)	<= 20.0 ppb	< 5.0
Trace Impurities – Tin (Sn)	<= 50.0 ppb	< 10.0
Trace Impurities – Titanium (Ti)	<= 10.0 ppb	< 1.0
Trace Impurities – Vanadium (V)	<= 10.0 ppb	< 1.0
Trace Impurities – Zinc (Zn)	<= 50.0 ppb	< 1.0
Trace Impurities – Zirconium (Zr)	<= 10.0 ppb	< 1.0
Particle Count – 0.5 µm and greater	<= 60 par/ml	31
Particle Count – 1.0 µm and greater	<= 10 par/ml	6

For Microelectronic Use

Storage Conditions: Recommended Storage Conditions: 15° – 100°F  
Country of Origin: US  
Packaging Site: Paris Mfg Ctr & DC



Phillipsburg, NJ 9001:2008, 14001:2004  
 Paris, KY 9001:2008  
 Mexico City, Mexico 9001:2008  
 Deventer, The Netherlands 9001:2008, 14001:2004, 13485:2003  
 Gliwice, Poland 9001:2008, 17025:2005  
 Selangor, Malaysia 9001:2008  
 Dehradun, India, 9001:2008, 14001:2004, 13485:2003  
 Mumbai, India, 9001:2008, 17025:2005  
 Panoli, India 9001:2008



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